

# Last updates on the lifetime saga

- •12/15 presented lifetime measurements of B+/B<sup>0</sup>. Bkg fixed from sideband (3 exps + gaussian). Non biasing cuts applied. Central values badly off.
- •01/05 oxford presented a lifetime measurement of B<sup>+</sup> with their method. Bkg modeled with 3 exps and 1 gaussian all treated as signal. Wider mass window. Central value ok, but large error and some doubts.
- •01/19 Saverio Da Ronco proposed a new measurement. Non biasing but strong cuts applied. Bkg modeled with 1 exp treated as signal and 1 gaussian. Central values ok, but fit not very convincing



## **Considerations**

- •Reducing bkg helps. Biasing but more effective cuts like  $L_{xy}$  have to be introduced sooner or later, better to start now
- •A wider mass window helps to fix better the bkg fraction, but this means more bkg and difficulties in treating the reflections and the B-type bkg
- •In my opinion it's not correct to treat bkg and signal in the same way, specially in the case of combinatorial bkg
- •Somehow the  $B^+ \rightarrow D^0 \pi$  has been chosen to be the "calibration" channel, but it's not a simple one



# **Fitting function**

#### Background:

$$L_{BG}^{comb}(c\mathbf{t}, \mathbf{s}_{t}) = Templ(c\mathbf{t}) - \frac{\mathbf{Misreconst. \& Combinatorial}}{\mathbf{Combinatorial}}$$

$$L_{BG}^{partial}(c\mathbf{t}, \mathbf{s}_{t}) = \left(\int \frac{1}{lp} \cdot e^{-\frac{t}{lp}} \frac{1}{\sqrt{2\mathbf{p} \cdot s \cdot \mathbf{s}_{t}}} \cdot e^{\frac{-(c\mathbf{t} - t)^{2}}{2(s \cdot \mathbf{s}_{t})}} \cdot dt\right) \cdot \mathbf{e}_{SVT}(c\mathbf{t})$$
Signal:

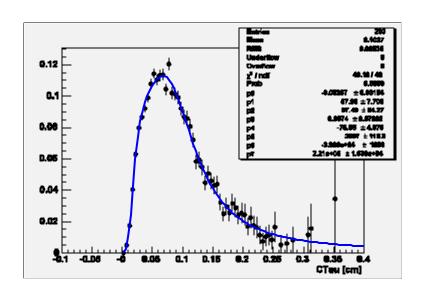
Partial reconstructed B

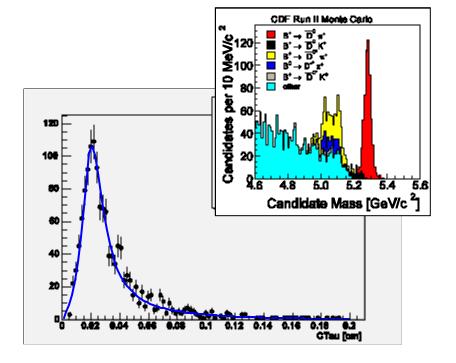
$$L_{SIG}(c\mathbf{t}, \mathbf{s_t}) = \left(\int \frac{1}{life} \cdot e^{-\frac{t}{life}} \frac{1}{\sqrt{2\mathbf{p} \cdot s \cdot \mathbf{s_t}}} \cdot e^{-\frac{(c\mathbf{t} - t)^2}{2(s \cdot \mathbf{s_t})}} \cdot dt\right) \cdot \mathbf{e}_{SVT}(c\mathbf{t})$$

Total function: 
$$L = L_{SIG} + fracb \cdot L_{BG}^{comb} + fracp \cdot L_{BG}^{partial}$$



## **B**+ lifetime-mass fit

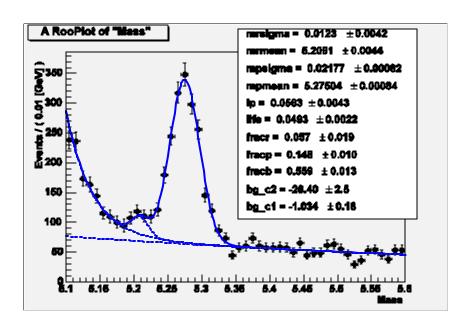


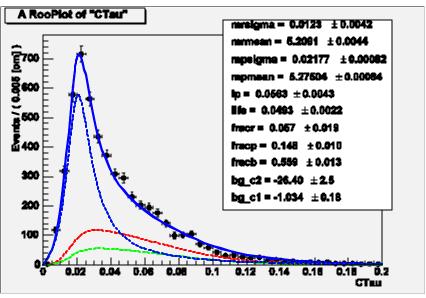


- $\varepsilon_{svt}$  calculated from offline quantities (systematic from bin by bin migration), including  $L_{xy}$  and I.P.
- •Upper side band used to build a template for combinatorial bkg lifetime distribution



## B+ lifetime-mass fit





- •Mass shapes of the reflection and the B-type background have to be modeled by a template (Donatella should provide me her).
- •A simple gaussian and exponential are used in the fit



## Lifetime conclusion

- •We are getting convinced that problems in lifetime measurements come from our poor understanding of the bkg
- •Though different methods model well signal, there is no clear way how to treat bkg in the correct way
- •02/16 Hadronic meeting will be devoted to evaluate pros and cons of different approaches focusing more on systematics rather than central values
- •In the case of D's we have high purity and pointing out the source of bias can be an important step to trust lifetime ratios



## D<sup>0</sup>/D<sup>+</sup> Status and Plan

- •Executables ready in 4.11.2 and 5.3.0
- Data samples
- -D\* stripped
- -D<sup>+</sup> ready to strip, last checks Space problem forseen
- •MC samples
- $-B \to D^*\pi \ 4.9.1$
- $-D^* \rightarrow D^0 \pi$  and  $D \rightarrow K \pi \pi 4.11.2$

It will take time to have all the samples in 5.3.0

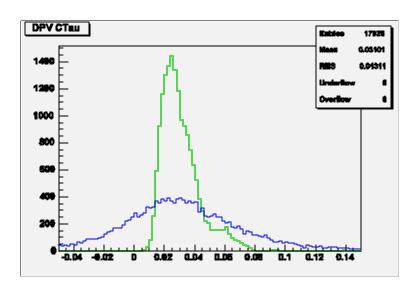
Problem between BGen and EvtGen

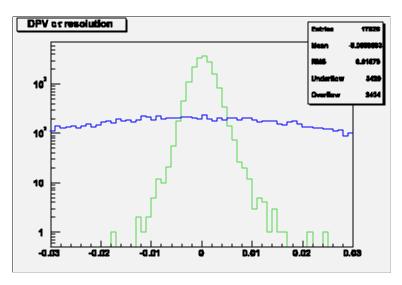
•Studies to handle no prompt fraction (starting from CDF6177)



# Primary vertex vs D\* vertex

Idea: if we are able to measure  $L_{xy}$  with respect to the  $D^*$  vertex we don't have to treat the no prompt  $D^0$  differently





- •CT resolution is very bad (300µm vs 20µm) even requiring hits in the innermost layers and loosing efficiency
- •L00 can help but probably not much